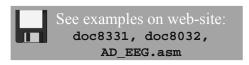


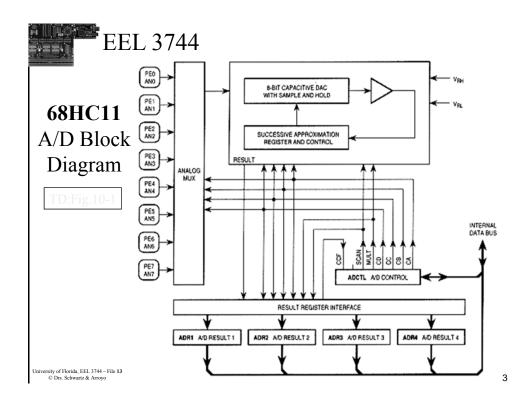
Menu

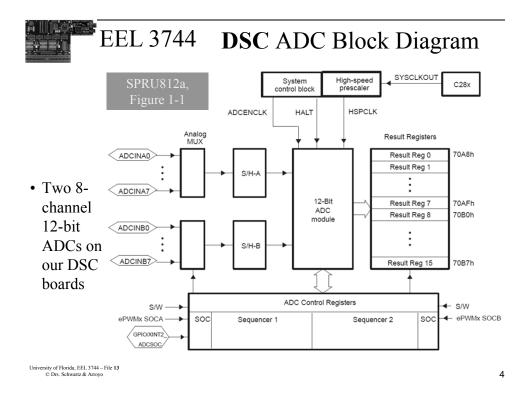
- A/D system on the 68HC11/12 & TI DSC F2833
- A/D system on the XMEGA
- A/D Converter Example: EEG
- Analog-to-Digital Conversion
 >Basic Charge-Redistribution A/D
- Analog-to-Digital Conversion
 - >What should the answers be?
 - >Example of 2-, 4-, ... 8-bit conversions



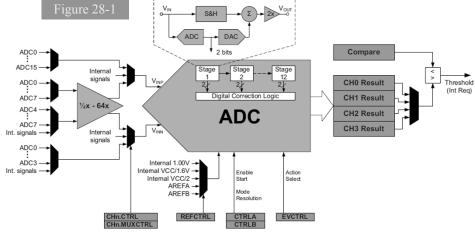


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EEL 3744 XMEGA ADC Block Diagram doc8331, Figure 28-1 ADC0 ADC15 Diagram Compare Compare



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See doc8331

Section 28.

EEL 3744

XMEGA ADC Features

- 12-bit resolution
- Up to 2Msamples/sec
 - > 2 inputs sampled simultaneously
 - > 4 inputs sampled within 1.5µs (667kHz)
- Differential or single-ended input
 - > Differential inputs with or without gain - Gains: $\frac{1}{2} \times$, $1 \times$, $2 \times$, $4 \times$, $8 \times$, $16 \times$, $32 \times$, $64 \times$
- Single scan or continuous scans
- Signed or unsigned results
- Internal and external reference options
- Optional event triggered conversion
- Four conversion channels with individual input control and result register
 - > Enable four parallel configurations and results

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6

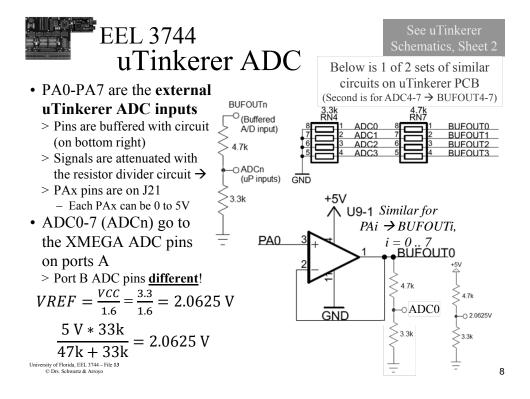


4.7k 2.0625V 3.3k

- "The uTinkerer, in an effort to reduce external circuitry size and complexity, has built in pre-amplifiers on ADC (port A) inputs AD0-7. The pre-amplifiers essentially remap the range of the ADC from 0 to 2.0625V to a more flexible 0 to 5V. The pre-amplifiers are designed to work with the internal ADC voltage reference (VREF) of VCC/1.6V (2.0625V when VCC=3.3V)."
- "It should be noted that even though the pre-amplifier circuit increases functionality, it also is another source for analog conversion error. For details, consult the included sensitivity analysis of the analog pre-amplifiers."
- ADC input pins AD8-11 are raw inputs. They connect directly to the ATxmega128A1U, i.e., with **no** resistor divider circuits.
- If put 5V on top, get 2.0625V at center tap.

$$VREF = \frac{VCC}{1.6} = \frac{3.3}{1.6} = 2.0625 \text{ V}$$
 $\frac{5 \text{ V} * 3.3 \text{ k}}{4.7 \text{ k} + 3.3 \text{ k}} = 2.0625 \text{ V}$

$$\frac{5 \text{ V} * 3.3 \text{ k}}{4.7 \text{ k} + 3.3 \text{ k}} = 2.0625 \text{ V}$$

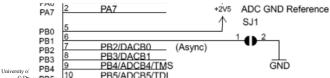


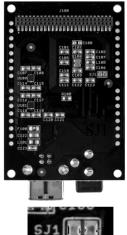


uPAD ADC

See uPAD Applications Manual: Analog In

- PORTB 0 is the input for the precision 2.5V analog reference
- PORTB 1 is the circuit GND reference input for differential analog measurements
- If you set the direction register for PORTB pins 0 or 1 to output (default for all pins is input) you risk destroying your board!
 - > Always use caution when using PORTB of the μPAD's XMEGA!!!
- The solder jumper SJ1 (on the bottom of the uPAD PCB, highlighted here), connects PB1 to board GND
 - > This GND connection serves as the negative input for differential measurements and the positive input terminal for differential measurements with gain via the XMEGA's PGA (Programmable Gain Array)

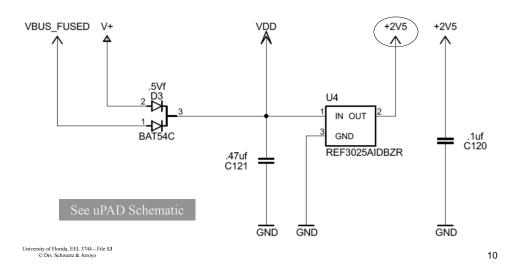






uPAD ADC

• ADC +2.5V reference schematic

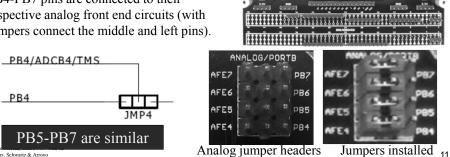


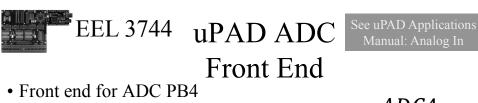


uPAD ADC

Manual: Analog In

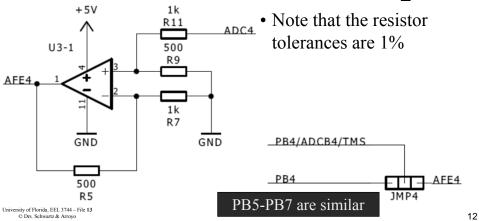
- This group of 4 selectors is used to control whether PORTB pins 4-7 are connected to their respective analog front end circuits, or their respective PORTB breakout connections in J9 of the µPAD Proto Base.
- Each pin (PB4-PB7) can be individually configured per its respective selector
- In the figure on the bottom right, all of the PB4-PB7 pins are connected to their respective analog front end circuits (with jumpers connect the middle and left pins).



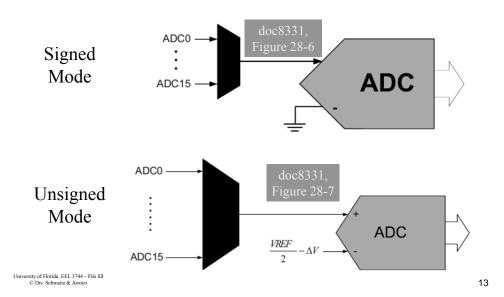


- AFE4 = ADC4 / 2
 - > See Application Manual for derivation

$$AFE4 = \frac{ADC4}{2}$$



EEL 3744 XMEGA ADC: Single-ended measurements

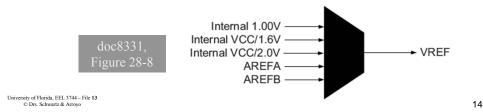




See doc8331, Section 28.5

XMEGA Voltage Reference

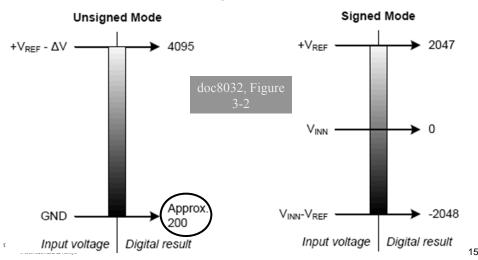
- Voltage reference (VREF) for the ADC is set to one of the following
 - >Internal 1.00V
 - >Internal Vcc/1.6V (=2.0625V for Vcc=3.3V)
 - >Internal Vcc/2V
 - >External voltage at AREF pin on PORTA
 - >External voltage at AREF pin on PORTB



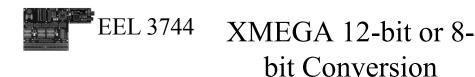
EEL 3744

XMEGA Offset in Unsigned mode

• Note the offset in unsigned mode



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- ADC can be configure to generate either an 8-bit or a 12-bit result
 - > Of course 8-bit results are available faster
- Result registers are 16 bits wide (i.e., two 8-bit registers)
 - > Data can be stored as right adjusted 16-bit values
 - Right adjusted means the 8 least-significant bits (lsb) are put in the low byte
 - Left adjusted means the 8 most-significant bits (msb) are put in the high byte
 - > A 12-bit result can be either left or right adjusted
- When in signed mode, the msb represent the sign bit
 - > The sign bit is sign-extend
 - For 12-bit right adjusted, bit 11 is repeated for bits 15-12
 - For 8-bit right adjusted, bit 7 is repeated for bits 15-8

See doc8331, Section 28.6

See doc8331

See doc8385

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- One 12-bit compare register
 - > Four Analog Comparators
 - Each of four ADC channels can be set for an interrupt when result is above or below the threshold
 - > Selectable propagation delay versus curent consumption
 - > Selectable hysteresis (none, small, large)
 - > Analog comparator output available on pin
 - > Flexible input selection
 - All pins on the port
 - Output from the DAC
 - Bandgap reference voltage
 - A 64-level programmable voltage scaler of the internal VCC voltage
 - > Interrupt and event generation on:
 - Rising edge, Falling edge, Toggle
 - > Window function interrupt and event generation on:
 - Signal above window, Signal inside window, Signal below window
- > Constant current source with configurable output pin selection
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See doc8331, Section 30

XMEGA Compare Function

• One 12-bit compare register

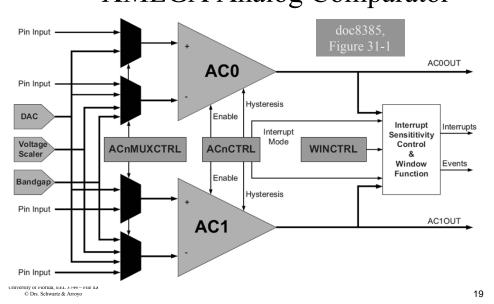
See doc8385, Section 31.2

- > Each of four ADC channels can be set for an interrupt when result is above or below the threshold
- > The input selection includes analog port pins, several internal signals, and a 64-level programmable voltage scaler
 - The analog comparator output state can also be output on a pin for use by external devices
- > The analog comparators are always grouped in pairs on each port, called analog comparator 0 (AC0) and analog comparator 1 (AC1)
 - They have identical behavior, but separate control registers
 - Used as pair, they can be set in window mode to compare a signal to a voltage range instead of a voltage level
 - PORTA and PORTB each has one AC pair, called ACA and ACB, respectively

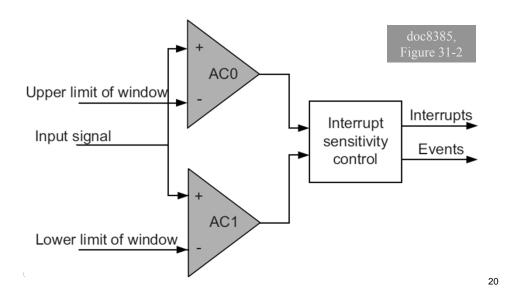
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EEL 3744 XMEGA Analog Comparator



EEL 3744 Analog Comparator Window Function





XMEGA Analog: Starting a Conversion

- Starting a conversion
 - >Write to the start conversion bit for one or more channels
 - >Use the event system to start one or several conversions
 - >If multiple start conversion bits are written, the scan starts from the lowest channel number
 - > 28.8.1 Input Source Scan:
 - For ADC Channel 0 it is possible to select a range of consecutive input sources that is automatically scanned and measured when a conversion is started
 - This is done by setting the first (lowest) positive ADC channel input using the MUX control register, and a number of consecutive positive input sources
 - When a conversion is started, the first selected input source is measured and converted, then the positive input source selection is incremented after each conversion until it reaches the specified number of sources to scan

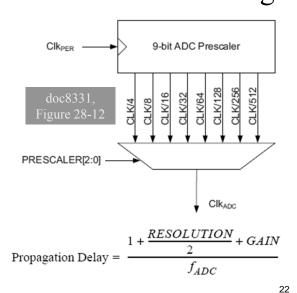
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XMEGA ADC Clock and Conversion Timing

- In below formula
 - > RESOLUTION = 8 or 12
 - > GAIN=0 (no gain) or 1 (gain)
 - $> f_{ADC} =$ sample rate
- The ADC clock rate is the limiting factor, <u>NOT</u> the propagation delay (due to the pipeline)
- The msb (most-significant bit) is converted first, the rest of the bits are converted in the
 - > next 3 ADC clock cycles for 8-bit
 - > next 5 ADC clock cycles for 12-bit
 - > Converting 1 bit takes $\frac{1}{2} T_{ADC}$
 - > Interrupt flag is set after result register is loaded

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EEL 3744 XMEGA ADC Timing

See doc8331, Section 28.9.1 (Single Conversion, no Gain)

• The writing of the start conversion bit, or the event triggering the conversion (START), must occur at least one peripheral clock cycle before the ADC clock cycle on which the conversion starts (indicated with the grey slope of the START trigger)

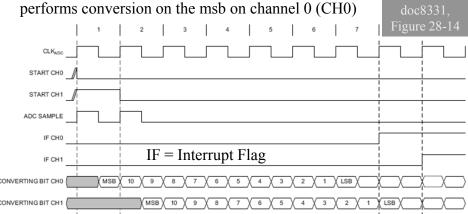
• The input source is sampled in the first half of the first cycle

CLKADO
START

ADC SAMPLE

EEL 3744 ADC Timing: Single Conversion, 2 Channels

- The pipelined design enables the second conversion to start on the next ADC clock cycle after the first conversion has started.
- Both conversions take place at the same time, but the conversion on ADC channel 1 (CH1) does not start until the ADC samples and



EEL 3744 XMEGA ADC CTRLA See doc8331, Section 28.16.1 — Control register A

• DMASEL: DMA Request Selection

> Can allow one DMA channel to serve more than one ADC channel

DMASEL[10]	Group Config	Description doc8331,
00	OFF	No combined DMA request Table 28-
01	CH01	Common request for ADC channels 0 & 1
10	CH012	Common request for ADC channels 0, 1 & 2
11	CH0123	Common request for ADC channels 0, 1, 2 & 3

• CHSTART[3:0]: Channel Start Single Conversion

> Setting bits will **start a conversion** on the corresponding ADC channel

Bit	7	6	5	4	3	2	1	0	_
+0x00	DMASE	EL[1:0]		CHSTA	RT[3:0]		FLUSH	ENABLE	1
Read/Write	R/W	R/W	R/W	R/W	R/W	R/W	R/W	R/W	•
Initial Value	0	0	0	0	0	0	0	0	
	a, EEL 3744 – File 13 artz & Arroyo		AD	Cn_CTRL	A, n=A,B			:	25



- CHSTART[3:0]: Channel Start Single Conversion
 - > Setting bits will **start a conversion** on the corresponding ADC channel; if several started at same time, lowest channel will start 1st
- FLUSH: Pipeline Flush
 - > Set to flush the ADC pipeline
 - ADC clock will restart on next peripheral clock edge & resume where left off
 - Pending conversion will enter the ADC pipeline and complete
 - > All conversions are aborted and lost
- ENABLE: Enable
 - > Set this bit to enable the ADC

Bit	7	6	5	4	3	2	1	0	_
+0x00	DMAS	EL[1:0]		CHSTA	RT[3:0]		FLUSH	ENABLE	
Read/Write	R/W	R/W	R/W R/W R/W		R/W	R/W	R/W		
Initial Value	0	0	0	0	0	0	0	0	
	ı, EEL 3744 – File 13 artz & Arroyo		AD	Cn_CTRI	LA, n=A,B			2	26



ADC CTRLB – ADC Control register B

- IMPMODE: Gain Stage Impedance Mode
 - > 0 = high impedance sources; 1 = low impedance sources
- CURRLIMIT[1:0]: Current Limitation
 - > Control current consumption by reducing the max ADC sample rate
- CONVMODE: Conversion Mode
 - > 0 = unsigned mode; 1 = signed
- FREERUN: Free Running Mode
 - > 0 = single scan
 - > 1 = free running mode
 - ADC channels defined in EVCTRL register are swept repeatedly

Bit	7	6	5	4	3	2	1	0	
+0x01	IMPMODE	CURRLIMIT[1:0]		CONVMODE	FREERUN	RESOLUTION[1:0]		-	
Read/Write	R/W	R/W	R/W	R/W	R/W	R/W	R/W	R	
Initial Value	0	0	0	0	0	0	0	0	
University of Florida © Drs. Schwi	, EEL 3744 – File 13 artz & Arroyo		AI	OCn_CTRL	B, n=A,B				27



See doc8331, Section 28-16.2 ADC CTRLB – ADC Control register B

- FREERUN: Free Running Mode
 - > 0 = single scan
 - > 1 = free running mode
 - ADC channels defined in EVCTRL register are swept repeatedly
- RESOLUTION[1:0]: Conversion Result Resolution

	RESOLU	UTION[10]	Group	Config	Description			
	00		12	-bit	12-bit result,	right justi	fied	
doc8331,		01	-		Reserved			
Table	e 28-4 10 11		8-	bit	8-bit result, r	ied		
			Left 12-bit		12-bit result,	left justifi	ed	
Bit	7	6	5	4	3	2	1	0
+0x01	IMPMODE	CURRLIMIT	[1:0]	CONVMOD	E FREERUN	RESOLU	TION[1:0]	-
Read/Write	R/W	R/W	R/W	R/W	R/W	R/W	R/W	R
Initial Value	0	0	00	0	0	0	0	0
	ı, EEL 3744 – File 13 artz & Arroyo		\overline{AD}	Cn_CTR	LB, n=A,B			28



ADC REFCTRL -

Reference Control register

- REFSEL[2:0]: Reference Selection
 - > Selects the reference for the ADC

	R	EFSEL[10]	Group Config	Description
		000	INT1V	10/11 of bandgap (1.0V)
		001	INTVCC	Vcc/1.6
doc833		010	AREFA	External ref from AREF pin or PORT A
Table 28	8-5	011	AREFB	External ref from AREF pin or PORT B
	П	100	INVCC2	Vcc/2
		101-111	-	Reserved

- BANDGAP: Bandgap Enable
- TEMPREF: Temperature Reference Enable

Bit	7	6	5	4	3	2	1	0	_
+0x02	-		REFSEL[2:0]		-	-	BANDGAP	TEMPREF	
Read/Write	R	R/W	R/W	R/W	R	R	R/W	R/W	•
Initial Value	0	0	0	0	0	0	0	0	
University of Florida © Drs. Schwa			ADC	n_REFCT	TRL, n=A,E	3		2	29



ADC EVCTRL – Event Control register

• SWEEP[1:0]: Channel Sweep

> Control which ADC channels are included in a channel sweep triggered by the event or when in free running mode

	SWEEP[10]	Group Config	Active ADC channels for channel sweep
	00	0	Only ADC channel 0
doc833		01	ADC channels 0 and 1
Table 28	3-6 10	012	ADC channels 0, 1, and 2
	11	0123	ADC channels 0, 1, 2, and 3

Bit	7	6	5	4	3	2	1	0
+0x03 SW		P[1:0]	EVSEL[2:0]				EVACT[2:0]	
Read/Write	R/W	R/W	R/W	R/W	R/W	R/W	R/W	R/W
Initial Value	0	0	0	0	0	0	0	0
University of Florida, l © Drs. Schwart			ADO	n_EVCT	RL, n=A,B			30



ADC EVCTRL – Event

Control register

• EVSEL[2:0]: Event Channel Input Select

- > Selects which event channel trigger which ADC channel (ch)
- > Event ch with lowest # will trigger ADC ch0, the next ADC ch1, ...

	1	EVSEL[10]	Group Config	Selecte	d event lines							
		000	0123	Event c	hannel 0, 1, 2,	and 3 as se	elected inputs					
		001	1234	Event c	hannel 1, 2, 3,	and 4 as se	elected inputs					
		010	2345	Event c	hannel 2, 3. 4,	and 5 as se	elected inputs					
doc8.	331	011	3456	Event c	hannel 3, 4, 5,	and 6 as se	elected inputs					
Table		100	4567	Event c	hannel 4, 5, 6,	and 7 as se	elected inputs					
14010		101	567	Event c	hannel 5, 6, ar	d 7 as sele	cted inputs					
		110	67	Event c	hannel 6, and	7 as selecte	d inputs	puts				
		111	7	Event c	hannel 7 as se	lected inpu	t					
Bit	7	6	5	4	3	2	1					
+0x03		SWEEP[1:0]		EVSEL[2:0]			EVACT[2:0]					
Read/Write	R/W	V R/W	R/W	R/W	R/W	R/W	R/W					
Initial Value	0	0	0	0	0	0	0					
University of Florida © Drs. Schw	a, EEL 3744 – F artz & Arroyo	file 13	ADCn	_EVCT	TRL, n=A,B							



ADC EVCTRL – Event Control register

- EVACT[2:0]: Event Mode
 - > Selects and limits how many of the selected event input channels are used
 - > Further limits the ADC triggers

EVACT[10]	Group Config	Selected	Selected event lines				31,		
000		None	No event	inputs			Table 2	28-8		
001		CH0	Event ch	with lowest #	defined by	EVSEL trigg	ers conv on	ADC ch 0		
010		CH01	" 2 lowes	t # " on ADC	chs 0 & 1					
011		CH012	" 3 lowes	' 3 lowest # " on ADC chs 0, 1, & 2						
100		CH0123	Event ch	Event ch defined by EVSEL triggers conversion on ADC chs 0-3						
101		SWEEP	One sweep of all ADC chs defined by SWEEP on incoming event channel with the lowest # defined by EVSEL							
110		SYNC SWEEP				ined by SWE. ADC flushe		_		
111		-	Reserved			ADCn E	VCTRL, 1	n=A,B		
Bit	7	6	5	4	3	2	1	0		
+0x03	s	WEEP[1:0]		EVSEL[2:0]			EVACT[2:0]			
Read/Write	R/W	R/W	R/W	R/W	R/W	R/W	R/W	R/W		
Initial Value	0	0	0	0	0	0	0	0 -		

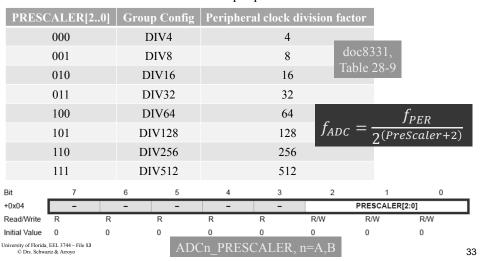


ADC PRESCALER –

Clock Prescaler register

• PRESCALER[2:0]: Prescaler Configuration

> Defines the ADC clock relative to the peripheral clock





ADC INTFLAGS – Interrupt Flag register

• CH[3:0]IF: Interrupt Flags

- > Set when the ADC conversion is complete for the corresponding ADC channel
- > If an ADC channel is configured for compare mode, the corresponding flag will be set if the compare condition is met
- > CHnIF is automatically **cleared** when the ADC channel n **interrupt vector is executed**
- > Writing a one to the flag's bit location will clear the flag

Bit	7	6	5	4	3	2	1	0			
+0x06	-	-	-	-	CH[3:0]IF						
Read/Write	R	R	R	R	R/W	R/W					
Initial Value	0	0	0	0	0 0 0 0						
University of Florida, © Drs. Schwa		AD	OCn_CHx_	_INTFLA	AGS, x=0,1	,2,3, n=A	,В	3	34		



ADC CTRL – Channel

Control register

• START: START Conversion on Channel

> Setting this bit will start a conversion on the channel

> The bit is cleared by hardware when the conversion has started

- > Setting this bit when it already is set will have no effect
- > Writing or reading this bit is equivalent to writing the CH[3:0]START bits in CTRLA (Control register A)

• GAIN[2:0]: Gain Factor

> These bits define the gain factor for the ADC gain stage

		Config	Factor
	000	1X	1x
	001	2X	2x
	010	4X	4x
,	011	8X	8x
	100	16X	16x
	101	32X	32x
	110	64X	64x
	111	DIV2	¹∕2 X
	2	1	0

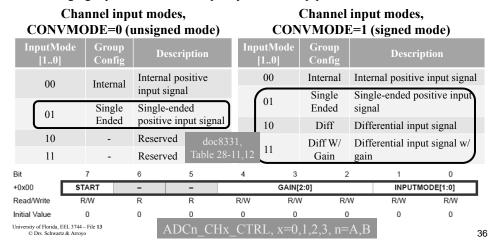
Table 28-10

Bit	7	6	5	4	3	2	1	0
+0x00	START	-	-		GAIN[2:0]	INPUTMODE[1:0]		
Read/Write	R/W	R	R	R/W	R/W	R/W	R/W	R/W
Initial Value	0	0	0	0	0	0	0	0
University of Florida, © Drs. Schwar			ADCn_Cl	Hx_CTRI	∠, x=0,1,2,	3, n=A,B		:



ADC CTRL - Channel Control register

- INPUTMODE[1:0]: Channel Input Mode
 - > These bits define the channel mode
 - > Changing input mode will corrupt any data in the pipeline





ADC MUXCTRL - ADC Channel MUX Control registers

• MUXPOS[3:0]: MUX Selection on Positive ADC

INPUTMODE [1:0] = 01 (single-ended)

				- 1111	UTMODI	հլուսյ – (m (singic	-cnuc		
Inpu	ıt				[see manual for others]					
	se bits defi he positive				MUXPOS [30]	Group Config	Descript	ion		
					0000	PIN0	ADC0 pii	1		
				doc8331	, 0001	PIN1	ADC1 pii	1		
				Table 28-	0010	PIN2	ADC2 pii	ı		
					0011	PIN3	ADC3 pii	n		
						PINx	ADCx pii	ı		
					1111	PIN15	ADC15 p	in		
Bit	7	6	5	4	3	2	1	0		
+0x01	-		MUXPO	OS[3:0]		М	UXNEG[2:0]			
Read/Write	R	R/W	R/W	R/W	R/W	R	R/W	R/W		
Initial Value	0	0	0	0	0	0	0	0		
University of Florida, I © Drs. Schwart		ADCn_	CHx_MU	JXCTRL,	x=0,1,2,3, 1	n=A,B				



ADC MUXCTRL – ADC Channel MUX Control registers

• MUXNEG[2:0]: MUX Selection on Negative ADC Input

- > These bits define the MUX selection for the negative ADC input when differential measurements are done
- > For internal or single-ended measurements, these bits are not used

Bit	7	6	5	4	3	2	1	0	
+0x01	-		MUXP	OS[3:0]			MUXNEG[2:0]		
Read/Write	R	R/W	R/W	R/W	R/W	R	R/W	R/W	_
Initial Value	0	0	0	0	0	0	0	0	
University of Florida, © Drs. Schwa		ADCn_	CHx_MU	JXCTRL,	x=0,1,2,3,	, n=A,B			38



ADC Result Registers

- For all result registers and with any ADC result resolution, a signed number is represented in 2's complement form, and the MSB represents the sign bit
- The RESL and RESH register pair represents the 16-bit value, ADCRESULT
 - > The low byte of the 16-bit register must be read before the high byte
 - > When the low byte register is read by the CPU, the high byte of the 16-bit register is copied into the temporary register in the same clock cycle as the low byte is read
 - > When the high byte is read, it is then read from the temporary register

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EEL 3744 ADC RESH – Channel n Result register High

- 12-bit Mode, Left Adjusted
 - > RES[11:4]: Channel Result High
 - These are the eight MSBs of the 12-bit ADC result
- 12-bit Mode, Right Adjusted
 - > RES[11:8]: Channel Result High
 - These are the four MSBs of the 12-bit ADC result
- 8-bit Mode

> These bits will be the extension of the sign bit, CHRES7, when the ADC works in signed mode, and set to zero when the ADC works in single-ended mode

	Bit	7	6	5	4	3	2	1	0
12-bit, left.					[11:4]				
12-bit, right	+0x05					RES[11:8]			
8-bit		-	-	-	-	-	-	-	-
	Read/Write	R	R	R	R	R	R	R	R
	Initial Value	0	0	0	0	0	0	0	0



ADC RESL – Channel n Result register Low

- 12- or 8-bit Mode, Right Adjusted
 - > RES[7:0]: Channel Result Low
 - These are the eight LSBs of the ADC result
- 12-bit Mode, Left Adjusted
 - > RES[3:0]: Channel Result Low
 - These are the four LSBs of the 12-bit ADC result

	Bit	7	6	5	4	3	2	1	0
12-/8-bit, right	+0x04				RES	[7:0]			
12-bit, left.	*0.04		RES	[3:0]		-	-	-	-
	Read/Write	R	R	R	R	R	R	R	R
	Initial Value	0	0	0	0	0	0	0	0
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ADCn_CHx_RES, x=0,1,2,3, n=A,B



EEL 3744 ADC SCAN – Channel Scan register

- Scan is enabled when COUNT is set differently than 0
- This register is available only for ADC channel 0
- OFFSET[3:0]: Positive MUX Setting Offset
 - > The channel scan is enabled when COUNT \neq 0 and this register contains the offset for the next input source to be converted on ADC channel 0 (CH0)
 - > The actual MUX setting for positive input equals MUXPOS + OFFSET. The value is incremented after each conversion until it reaches the maximum value given by COUNT
 - > When OFFSET = COUNT, OFFSET will be cleared on the next conversion

Bit	7	6	5	4	3	2	1	0	
+0x06		OFFSI	ET[3:0]		COUNT[3:0]				SCAN
Read/Write	R/W	R/W	R/W	R/W	R/W	R/W	R/W	R/W	
Initial Value	0	0	0	0	0	0	0	0	

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EEL 3744 ADC SCAN – Channel Scan register

- COUNT[3:0]: Number of Input Channels Included in Scan
 - > This register gives the number of input sources included in the channel scan
 - > The number of input sources included is COUNT + 1
 - > The input channels included are the range from MUXPOS + OFFSET to MUXPOS + OFFSET + COUNT

Bit	7	6	5	4	3	3 2 1 0				
+0x06		OFFSI	ET[3:0]			COUNT[3:0]				
Read/Write	R/W	R/W	R/W	R/W	R/W	R/W	R/W	R/W		
Initial Value	0	0	0	0	0	0	0	0		

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ADCn CHx SCAN, x=0,1,2,3, n=A,B



ADC Register Summary

Address	Name	Bit 7	Bit 6	Bit 5	Bit 4	Bit 3	Bit 2	Bit 1	Bit 0		
+0x00	CTRLA	DMASE	EL[1:0]		CH[3:0	START		FLUSH	ENABLE		
+0x01	CTRLB	IMPMODE	DE CURRLIMIT[1:0] CONVMODE FREERUN RESOLUTION[1:0]		JTION[1:0]	-					
+0x02	REFCTRL	-		REFSEL[2:0]		-	- BANDGAP T				
+0x03	EVCTRL	SWEE	P[1:0]		EVSEL[2:0]		EVACT[2:0]				
+0x04	PRESCALER	-	-	-	-	-	PRESCALER[2:0]				
+0x05	Reserved	-	-	-	-	-	-	-	-		
+0x06	INTFLAGS	-	-	-	-		CH[3:0]IF				
+0x10	CHORESL	CHORES[7:0]									
+0x11	CH0RESH		CH0RES[15:8]								
+0x12	CH1RESL				CH1R	ES[7:0]					
+0x13	CH1RESH				CH1RE	S[15:8]					
+0x14	CH2RESL				CH2R	ES[7:0]					
+0x15	CH2RESH				CH2RE	S[15:8]					
+0x16	CH3RESL				CH3R	ES[7:0]					
+0x17	CH3RESH				CH3RE	S[15:8]					
+0x18	CMPL		CMP[7:0]								
+0x19	CMPH				CMP	[15:8]					
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ADC Register Requirements For Our Lab

- Enable ADC: ADCA CTRLA
- Set reference: ADCA REFCTRL
 - > You need to use the value that will make VREF=External AREF pin or PORTB
- Set sample time: ADCA PRESCALER
 - > Al Gore suggests using DIV512
- Set mode (unsigned or signed; single scan or free running)

ADCA CTRLB

- > I suggest FREERUN and 8-bit right-adjusted
- Set ADC pin for input: PORTA DIR
- Start the scan: ADCA CH0 CTRL
- Wait for result (or use interrupts): ADCA CH0 INTFLAGS
- Get Result: ADCA CH0 RES
 - > This might be two bytes to deal with, depending on the number of bits and right- or left-adjusted

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A/D Definitions

- Analog: Continuous in time and voltage
- **Digital**: Discrete in time (sampling) and voltage (a fixed set of possible values, e.g., if 3 bits, then 2³=8 possible values)
- **Span**: Range of possible analog voltages > Span = $V_H V_L$
 - > If $V_H = 5$ V and $V_L = 0$ V, Span = 5V
- **Resolution** (Δ): Smallest change in an input that will produce a change in the output
 - $>\Delta$ = Span / 2ⁿ, where n is the number of bits - If 2.37 V to 2.38 V is the smallest change allowed, Δ = 0.01 V
 - >If V_H =5V & V_L =0, and n = 8, then $\Delta = 5V / 2^8 = 19.5 \text{ mV}$

University of Florida, EEL 3744-File 13 - If n = 16, $\Delta = 5$ V / $2^{16} = 76.2$ μ V

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A/D Definitions

- Dynamic Range:
 - >D.R. = Largest Voltage / Smallest Voltage
 - >D.R. = $V_{max} / V_{min-measurable}$, often measured in dB $V_{min-measurable} = \Delta$
 - >For noise in a system, replace Δ with V_{noise}
 - >D.R._{dB} = 20 log($V_{max} / V_{min-meas}$) = 20 log(V_{max} / Δ)
- >D.R._{dB} = 20 log($V_{max} / [Span / 2^n]$)
- >If V_{min} =0, then D.R._{dB} = $20 \log(V_{max} / [V_{max} / 2^n])$
 - $D.R._{dB} = 20 \log(2^n) = n \times 20 \log(2) \approx 6 \times n dB$
- >Example: Given 8-bit A/D, range of 0V to 5V
 - Span = $V_H V_L = 5 0 = 5V$
 - $-\Delta = \text{Span} / 2^{n} = 5 \text{V} / 2^{8} = 19.5 \text{ mV}$
 - $-D.R._{dB} = 20 \log(V_{max} / \Delta) = 20 \log(5V / 19.5mV) = 48.2 dB$
- $-D.R._{dB} \approx 6n dB = 6*8 dB = 48 dB$ University of Florida, EEL 3744 File 13
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A/D Definitions

- Accuracy: Closeness of a measurement to its actual value
 - >Example for resolution, $\Delta = 19.5 \text{ mV}$
 - If measured 37 mV, then 100% * 19.5/37 = 52.7% (pretty bad!)
 - If measured 370 mV, then 100% * 19.5/370 = 5.27%
 - If measured 3.7 V, then 100% * 0.0195/3.7 = 0.527%
- Nyquist-Shannon Theorem: Sampling frequency must be at least twice the highest frequency (in order to properly reconstruct the original signal)
 - > $f_{sample} \ge 2 \times f_{max} \rightarrow T_{sample} \le 1 / (2 f_{max})$
 - T_{sample} is the maximum A/D conversion time necessary to accurately reproduce the original signal

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Sampling Rates

- Telephone (narrowband): 8 kHz
 Wideband telephone, VoIP, VVoIP: 16 kHz
- MPEG Audio: 11.025 kHz
- Audio CDs sample at 44.1 kHz (and uses 16-bits)
- Profession audio sampling rate using tape recorders, video servers, etc: 48 kHz
- First commercial digital audio recorders (1970s): **50 kHz**
- Pro recording equipment for making CDs: 88.2 kHz
- DVD-audio, Blue-ray disk audio, HD DVD audio: 96kHz
- Recording equipment for DVD-audio, Blue-ray disk audio, HD DVD audio: 192 kHz
- Noise kills dynamic range

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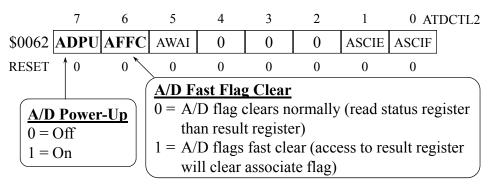
Dynamic Range Examples

- Dynamic Ranges for various systems
 - >8-track tapes: 50 dB
 - >Dolby B: 62 dB
 - >CDs (16-bit): 96 dB (theoretical)
 - >Digital Audio (16-bit): 96 dB (theoretical)
 - Observed 16-bit digital audio: 90 dB
 - >Digital Audio (20-bit): 120 dB (theoretical)
 - >Digital Audio (24-bit): 144 dB (theoretical)

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EEL 3744 68HC12 ATDCTL2: ATD Control Register 2 (A/D Power-Up)



• It takes 100μs for the charge pump to stabilize, so turn A/D power on at least 200 E-clocks (for E=2 MHz, 0.5μs) before use

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EEL 3744 68HC12 ATDCTL2: ATD Control Register 2 (A/D Power-Up)

	7	6	5	4	3	2	1	0 AT	DCTL2
\$0062	ADPU	AFFC	AWAI	0	0	0	ASCIE	ASCIF	
RESET	0	0	0	0	0	0	0	0	

- AWAI: A/D stop in wait mode
- ASCIE: A/D sequence complete interrupt enable >0 = disables A/D interrupt; 1 = enables A/D interrupt
- ASCIF: A/D sequence complete interrupt flag >0 = no A/D interrupt; 1 = A/D interrupt occurred

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68HC12 ATDCTL4: A/D Control Register 4 (Sample and Conversion Times)

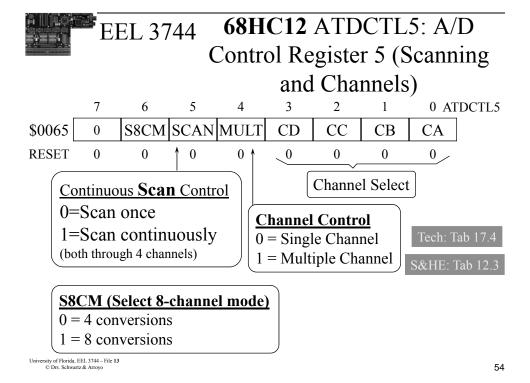
	7	6	5	4	3	2	1	0 AT	DCTL4
\$0064	0	SMP1	SMP0	PRS4	PRS3	PRS2	PRS1	PRS0	
RESET	0	0	0	0	0	0	0	1	
			S	S&HE: F	ig 12.2 &	Fig 12.3	& Tab 1	2.1 & Tal	b 12.2

- PRS4:0 are the A/D prescaler bits for the conversion times
 Set these bits so the A/D clock frequency is between 2 MHz and 500 KHz
 - For our board with E = 2 MHz, PRS=0 (=> 1 MHz) or 1 (=> 500 KHz)
- SMP1:0 are the A/D sample time bits and determine the time a signal is sampled (see S&HE: Fig 12.2 & Tab 12.2)
 - > This will determine the total conversion time in E-clocks
 - Minimum is 18 E-clocks; maximum is 32 E-clocks (see S&HE: Tab 12.2)
- Normally, leave these as all at zero (or the PRS0=1)

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- If MULT=0 (single channel selected)
 - >CD should be 0
 - >CC:CA determine the single selected channel
 - Example CC:CA=101 => A/D channel 5 is selected
- If MULT=1 (multiple channels selected)
 - >4-channel conversion
 - CB & CA have no effect
 - CC determines the group of four channels used (CD is ignored)
 - >8-channel conversion
 - CC, CB & CA have no effect
 - CD should be 0
- See Tech: Tab 17.4

Гаb 17.4 s&не

Tech: Tab 17.4

S&HE: Tab 12.3

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68HC12 ATDSTAT: A/D

Status Registers (High Byte)

				ATD	STATH				
	7	6	5	4	3	2	1	0	
\$0066	SCF	0	0	0	0	CC2	CC1	CC0	
RESET		0	0	0	0	0	0	0	

- SCF: Sequence complete flag
 - >Set when a conversion sequence (4 or 8 samples) have been taken (when SCAN=0) or when first sequence has been taken (when SCAN=1)
- CC2-CC0: Conversion counter for the current sequence
 - >CC2:0 give the binary code of the register that will be written next

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68HC12 ATDSTAT: A/D

Status Registers (Low Byte)

	7	6	5	1	3	2	1	ATDSTATL	
	,	U					1	U	
\$0067	CCF7	CCF6	CCF5	CCF4	CCF3	CCF2	CCF1	CCF0	
RESET	0	0	0	0	0	0	0	0	

- CCF7-CCF0: Conversion complete flags
 - >Each flag is associated with an A/D result register
 - >Each bit is set at the end of the conversion
 - >Clear a bit by one of the below techniques
 - If AFFC in ADCTL2 is clear (fast clear = 0, default)
 - ©Clear by reading ATDSTAT then reading the corresponding A/D result register
 - If AFFC in ADCTL2 (fast clear = 1)
 - *Clear by reading the corresponding A/D result register (no read of ADSTAT is necessary)

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EEL 3744 **68HC12** ADR0H-ADR7H:

A/D Result Registers

- High A/D result registers are used for 8-bit A/D
- These registers are read only

		\sim			2				
	7	6	5	4	3	2	1	0	
\$0070	Bit7	-	-	-	-	-	-	Bit0	ADR0H
	7	6	5	4	3	2	1	0	
\$0072	Bit7	-	-	-	-	-	-	Bit0	ADR1H
000									
	7	6	5	4	3	2	1	0	0
\$007C	Bit7	-	-	-	-	-	-	Bit0	ADR6H
	7	6	5	4	3	2	1	0	
\$007E	Bit7	-	-	-	-	-	-	Bit0	ADR7H

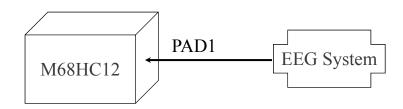
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A/D EEG Example with 68HC12

- ❖ Problem Statement
 - Collect 100 samples of an EEG signal sampled at 125Hz
 - Place the 100 samples starting at location EEG
 - The EEG signal is amplified and is presented as a 0-5V level analog signal to the A/D



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A/D EEG Example

- f_S =125Hz, T_S = 1/125 = 0.008s = 8ms, i.e., collect a sample every 8ms
- Let us use the RTI (real-time interrupt) system to generate the timing
 - > If RTICTL2:0 (RTR2:RTR0) are 010 then the system interrupts every 8.192ms for E=2 MHz (i.e., f = 1/T = 122Hz ≈ 125 Hz)
 - > Q: What would you do if we need a sample every 370µs?
- We'll use PAD1 and therefore set ATDCTL53:0 to 0001
- MULT=0 (single channel); SCAN=0 (scan once); S8CM=0 (4-channels)
- We will assume the data is noisy, so we'll take 4 quick samples and record the average of the four values
- ISR for RTI is (without D-Bug12) located at \$FFF0



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Analog/Digital Conversion

- A/D Conversion Method in the M68HC11
 - >Charge Distribution A/D (see RM Chapter 12)
 - The 68HC12's A/D is similar

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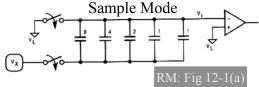


Basic Charge-Redistribution A/D

a) Sample Mode

the Total Charge: $Q_S = C V$ $Q_S = 16 (V_X - V_I)$

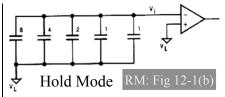
 $\therefore Q_S = 16 V_X$ (with $V_L = 0$)



b) Hold Mode (see figure, next column) $Q_{H} = (V_{L} - V_{i}) 16$

 $\therefore Q_H = -16 V_i$ (with $V_L = 0$)

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Since charge is conserved,

$$Q_{S} = Q_{H}$$

$$16 V_{X} = -16V_{i}$$

$$V_{X} = -V_{i}$$

$$\therefore V_{i} = -V_{X}$$

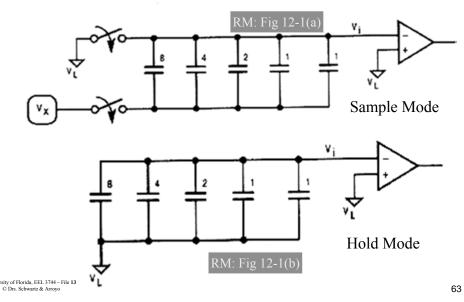
c) Approximation Mode

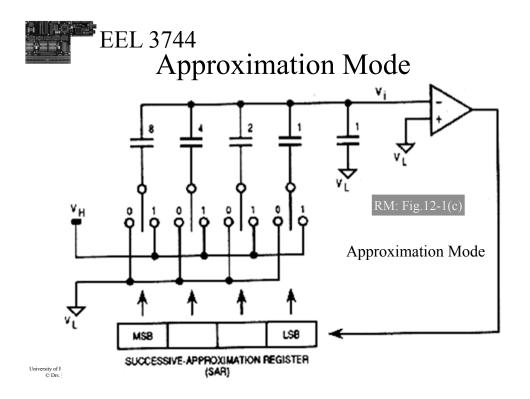
RM: Fig 12-1(c)

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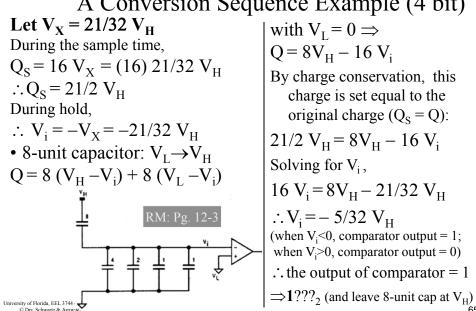
Sample Mode & Hold Mode





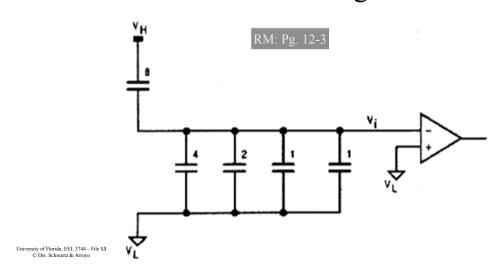


A Conversion Sequence Example (4 bit)



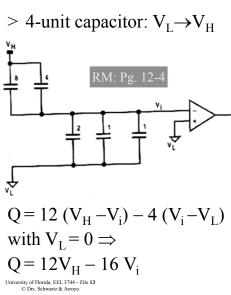
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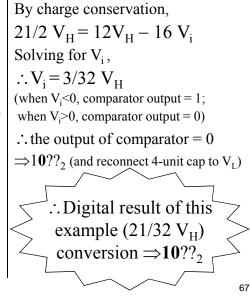
Eight-unit capacitor switched from low to high

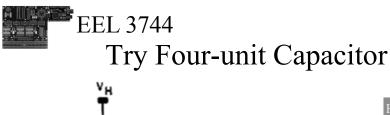


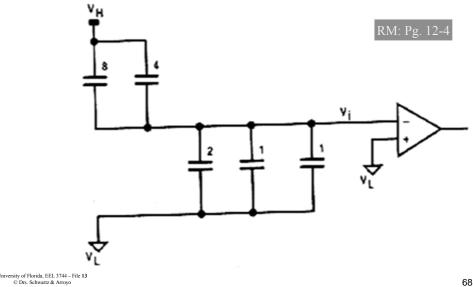
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A Conversion Sequence Example (4 bit)



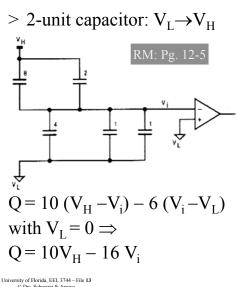








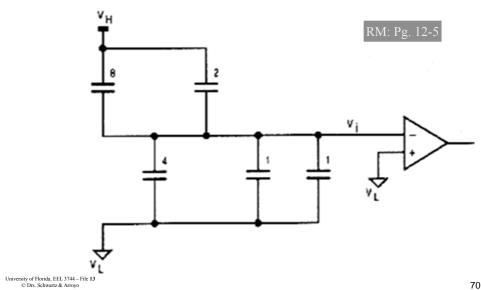
A Conversion Sequence Example (4 bit)



By charge conservation, $21/2 \text{ V}_{H} = 10 \text{ V}_{H} - 16 \text{ V}_{i}$ Solving for V_{i} , $\therefore \text{V}_{i} = -1/32 \text{ V}_{H}$ (when $\text{V}_{i} < 0$, comparator output = 1; when $\text{V}_{i} > 0$, comparator output = 0) $\therefore \text{the output of comparator} = 1$ $\Rightarrow 101?_{2} \text{ (and leave 2-unit cap at V}_{H})$ $\text{conversion} \Rightarrow 101?_{2}$

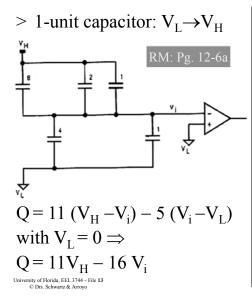


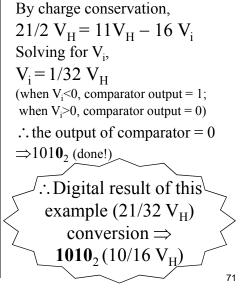
Try Two-unit capacitor

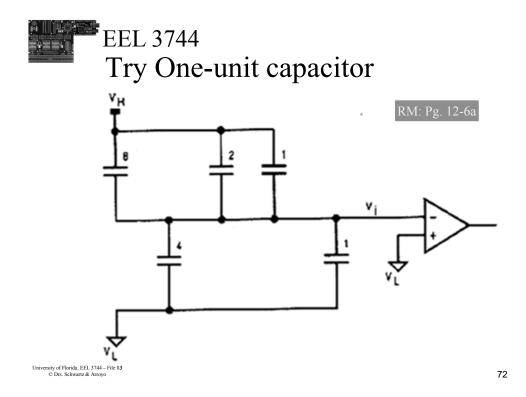




A Conversion Sequence Example (4 bit)



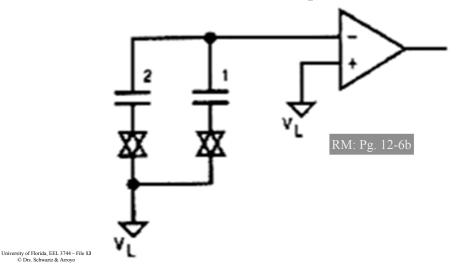


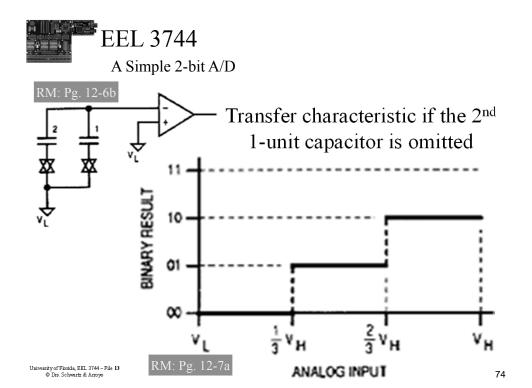




A Simple 2-bit A/D

A/D if the 2nd 1-unit capacitor is omitted

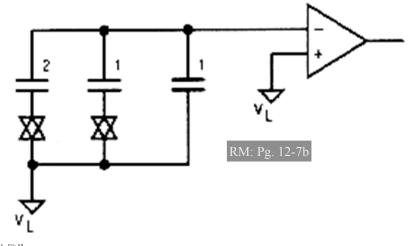




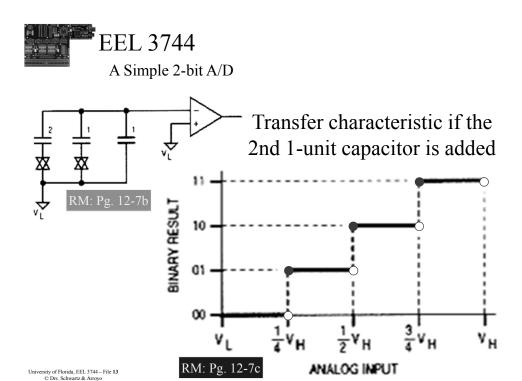


A Simple 2-bit A/D

A/D if the 2nd 1-unit capacitor is added

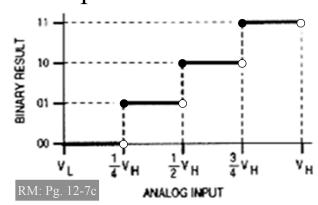


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A Simple 2-bit A/D



Example:

(ex)
$$V_X = 1/4 V_H \Rightarrow 01_2 (1/4 V_H)$$

$$V_X = 1/8 V_H \Rightarrow 00_2 (0 V_H)$$
; error by 1/8 V_H or 1/2 LSB

: This 2-bit A/D has a Quantization Error of -0/+1 LSB



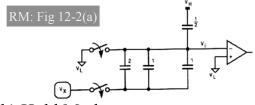
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Charge-Redistribution A/D with

a) Sample Mode ±1/2 LSB Quantization Error

a) Sample Mode $Q_S = 4(V_X - V_L) + 1/2 (V_H - V_L)$ with $V_L = 0 \Longrightarrow$

$$\therefore Q_S = 4V_X + 1/2 V_H$$

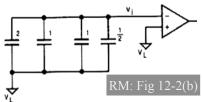


b) Hold Mode

$$\dot{Q}_{H} = 9/2 (V_{L} - V_{i})$$

$$\therefore Q_{H} = -9/2 V_{i} \text{ (with } V_{L} = 0)$$

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Since charge is conserved,

$$\begin{aligned} &Q_{S} = Q_{H} \\ &4V_{X} + 1/2 \ V_{H} = -9/2 \ V_{i} \\ &8V_{X} + V_{H} = -9V_{i} \\ &\therefore 9/8V_{i} = -V_{X} - 1/8V_{H} \end{aligned}$$

c) Approximation Mode

RM: Fig 12-2(c)

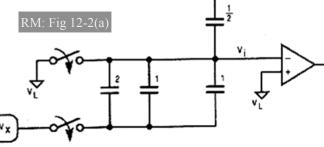
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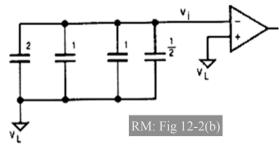
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Charge-Redistribution A/D with ±1/2 LSB Quantization Error

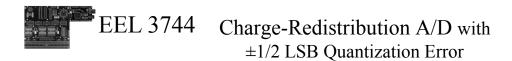
a) Sample Mode



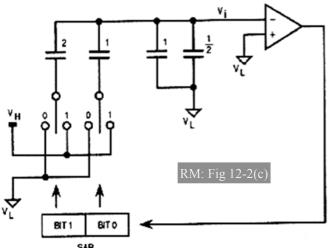
b) Hold Mode



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c) Approximation Mode

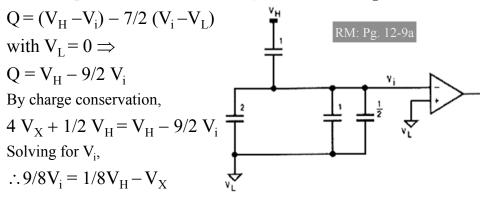


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EEL 3744 Charge-Redistribution A/D with ±1/2 LSB Quantization Error

> The Equivalent circuit for a digital result of 01₂:



: the output of comparator = 1 (\Rightarrow 01₂) if $V_X > 1/8 V_H$

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EEL 3744 Charge-Redistribution A/D with ±1/2 LSB Quantization Error

> The Equivalent circuit for a digital result of 10₂:

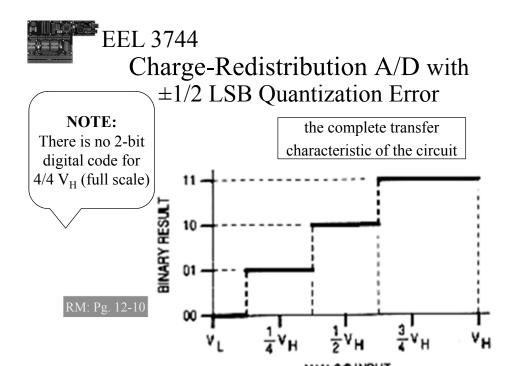
$$Q = 2 (V_H - V_i) - 5/2 (V_i - V_L)$$
with $V_L = 0 \Rightarrow$

$$Q = 2 V_H - 9/2 V_i$$
By charge conservation,
$$4 V_X + 1/2 V_H = 2 V_H - 9/2 V_i$$
Solving for V_i ,

: the output of comparator = 1 (\Rightarrow 10₂) if $V_X > 3/8 V_H$

 $\therefore 9/8V_i = 3/8V_H - V_X$

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Quantization in 2 bits

- Suppose your A/D Converter yields 2 bits
 - >What should the answers be?
 - >There are 4 bit patterns possible, mainly {00,01,10,11}:
 - -00 is the bit pattern for VRL $\{0 \le V_{\%} < 0.25\}$
 - -01 for 25% or 1/4 of (VRH-VRL) $\{0.25 \le V_{\%} < 0.50\}$
 - -10 for 50% or 1/2 of (VRH-VRL) $\{0.50 \le V_{\%} < 0.75\}$
 - -11 for 75% or 3/4 of (VRH-VRL) $\{0.75 \le V_{\%} < 1.00\}$
 - >Let V_{RH} =5V and V_{RL} =0V and if our unknown voltage is:
 - V_x =2.00V, then answer will be 01 for $V_{\%}$ = 2.00/5 or 40% of V_{RH}
 - V_x =1.25V, then answer will be 01 for $V_{\%}$ = 1.25/5 or 25% of V_{RH}
 - Vx=4.00V, then answer will be 11 for $V_{\%}$ = 4.00/5 or 80% of V_{RH}

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Quantization in 3 bits

- Suppose your A/D Converter yields <u>3 bits</u>
 - >There are 4 bit patterns possible, mainly {00,01,10,11}:
 - 000 is the bit pattern for VRL $\{0 \le V\% < 0.125\}$
 - 001 for 12.5% or 1/8 of (V_RH-V_RL) $\{0.125 \leq V_{\%} < 0.250\}$
 - 110 for 75% or 6/8 of (V_RH-V_RL) {0.75 \leq V%<0.875}
 - 111 for 87.5% or 7/8 of $(V_{RH}-V_{RL})$ {0.875 $\leq V_{\%}$ <1.00}
 - >Let V_{RH} =5V and V_{RL} =0V and if our unknown voltage is:
 - $V_x = 2.00$ V, the answer will be 011 for $V_{\%} = 2.00/5$ or 40% of V_{RH}
 - V_x =1.25 V, the answer will be 010 for $V_{\%}$ =1.25/5 or 25% of V_{RH}
 - V_x =4.00 V, the answer will be 110 for $V_{\%}$ =4.00/5 or 80% of V_{RH}

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Quantization in 4 bits

- Suppose your A/D Converter yields 4 bits
 - >There are 16 bit patterns possible, mainly {0000,0001,...,1110,1111}:
 - 0000 is the bit pattern for VRL $\{0 \le V\% < 0.0625\}$
 - 0001 for 6.25% or 1/16 of $(V_{RH}-V_{RL})$ {0.0625 \leq V%<0.125}
 - 1110 for 87.5% or 14/16 of $(V_{RH}-V_{RL})$ {**0.875** \leq **V%**<**0.9375**}
 - 1111 for 93.75% or 15/16 of $(V_{RH}-V_{RL})$ {**0.9375** \leq **V%**<**1.00**}
 - >Let V_{RH} =5V and V_{RL} =0V and if our unknown voltage is:
 - V_x =2.00V, the answer will be 0110 for $V_{\%}$ =2.00/5 or 40% of V_{RH}
 - V_x =1.25V, the answer will be 0100 for $V_{\%}$ =1.25/5 or 25% of V_{RH}
 - V_x =4.00V, the answer will be 1100 for $V_{\%}$ =4.00/5 or 80% of V_{RH}

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Quantization in 8 bits

- Now, if your A/D Converter yields <u>8 bits</u>
 - >There are 256 bit patterns possible, {00000000,00000001,...,11111110,11111111}
 - >Thus, 00000000 is the bit pattern for V_{RL} { $0 \le V_{\%} < 0.00390625$ }
 - > 00000001 for 0.390625% or 1/256 of (V_{RH} - V_{RL})
 - >11111111 for 99.609375% or 255/256 of (V_{RH} - V_{RL})
 - >Etc.

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Checking Your A/D

- If your A/D Converter yields 8 bits
 - - -00000000 is the bit pattern for V_{RL} $\{0 \le V_{\%} < 0.00390625\}$
 - 11111111 for 99.609375% or 255/256 of (V_{RH} - V_{RL})
 - -01001100 for 29.6875% or 76/256 of (V_{RH} - V_{RL})
 - >Then if you connect a "C" battery (with normal voltage of 1.5V) to, an ADC pin with V_{RH} =5V and V_{RL} =0V, then the A/D should yield \$4C = 76_{10} = %01001100
 - >If you get \$46 you are probably satisfied ...
 - >If you get \$35, your battery is probably dead ...
 - >But if you get larger than say \$50, for example, \$DE, then something is VERY wrong!!! How can a "C" battery >> 1.5V?

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The End!